

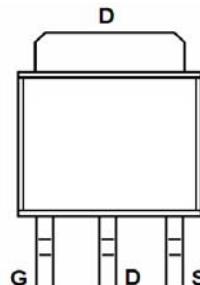
75V(D-S) N-Channel Enhancement Mode Power MOS FET

Features

- $V_{DS}=75V$; $I_D=60A$ @ $V_{GS}=10V$;
- $R_{DS(ON)}<8.5m\Omega$ @ $V_{GS}=10V$
- Special process technology for high ESD capability
- Special designed for Convertors and power controls
- High density cell design for ultra low R_{dson}
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation



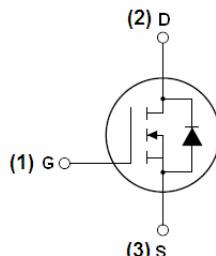
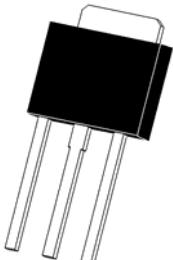
Lead Free



Marking and pin assignment

Application

- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply

PIN Configuration

Schematic diagram

TO-251 top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
MSN0860Z	MSN0860Z	TO-251-3L	-	-	-

Absolute Maximum Ratings ($T_c=25^\circ C$)

Parameter	Symbol	Value	Unit
Drain-Source Voltage ($V_{GS}=0V$)	V_{DS}	75	V
Gate-Source Voltage ($V_{DS}=0V$)	V_{GS}	± 20	V
Drain Current (DC) at $T_c=25^\circ C$	I_D (DC)	60	A
Drain Current (DC) at $T_c=100^\circ C$	I_D (DC)	42	A
Drain Current-Continuous@ Current-Pulsed ^(Note 1)	I_{DM} (pulse)	310	A
Peak diode recovery voltage	dv/dt	30	V/ns
Maximum Power Dissipation($T_c=25^\circ C$)	P_D	140	W
Derating factor		0.95	W/°C
Single pulse avalanche energy ^(Note 2)	E_{AS}	300	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	°C

Notes 1.Repetitive Rating: Pulse width limited by maximum junction temperature

2.EAS condition: $T_j=25^\circ C, V_{DD}=37.5V, V_G=10V, L=0.5mH$

Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R _{thJC}	1.05	°C/W
Thermal Resistance, Junction-to-Ambient (Maximum)	R _{thJA}	50	°C/W

Electrical Characteristics (T_C=25°C unless otherwise noted)

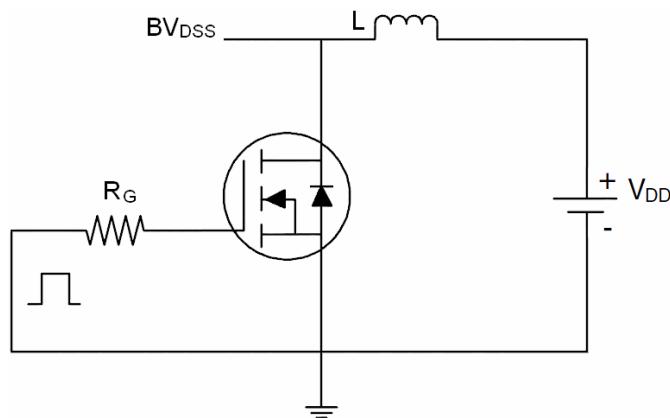
Parameter	Symbol	Condition	Min	Typ	Max	Unit
On/off states						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	75	84	-	V
Zero Gate Voltage Drain Current(T _C =25°C)	I _{DSS}	V _{DS} =75V, V _{GS} =0V	-	-	1	μA
Zero Gate Voltage Drain Current(T _C =125°C)	I _{DSS}	V _{DS} =75V, V _{GS} =0V	-	-	10	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2	3	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =30A	-	6.8	8.5	mΩ
Dynamic Characteristics						
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =30A		66	-	S
Input Capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V, F=1.0MHz		4400	-	PF
Output Capacitance	C _{oss}			340	-	PF
Reverse Transfer Capacitance	C _{rss}			260	-	PF
Total Gate Charge	Q _g	V _{DS} =30V, I _D =30A, V _{GS} =10V		100	-	nC
Gate-Source Charge	Q _{gs}			20	-	nC
Gate-Drain Charge	Q _{gd}			30	-	nC
Switching times						
Turn-on Delay Time	t _{d(on)}	V _{DD} =30V, I _D =2A, R _L =15Ω V _{GS} =10V, R _G =2.5Ω	-	17.8	-	nS
Turn-on Rise Time	t _r		-	11.8	-	nS
Turn-Off Delay Time	t _{d(off)}		-	56	-	nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}		-	-	80	A
Pulsed Source-drain current(Body Diode)	I _{SDM}		-	-	320	A
Forward on voltage ^(Note 1)	V _{SD}	T _j =25°C, I _{SD} =30A, V _{GS} =0V	-	-	1.2	V
Reverse Recovery Time ^(Note 1)	t _{rr}	T _j =25°C, I _F =75A, di/dt=100A/μs	-	-	36	nS
Reverse Recovery Charge ^(Note 1)	Q _{rr}		-	-	56	nC
Forward Turn-on Time	t _{on}	Intrinsic turn-on time is negligible(turn-on is dominated by L _s +L _D)				

Notes

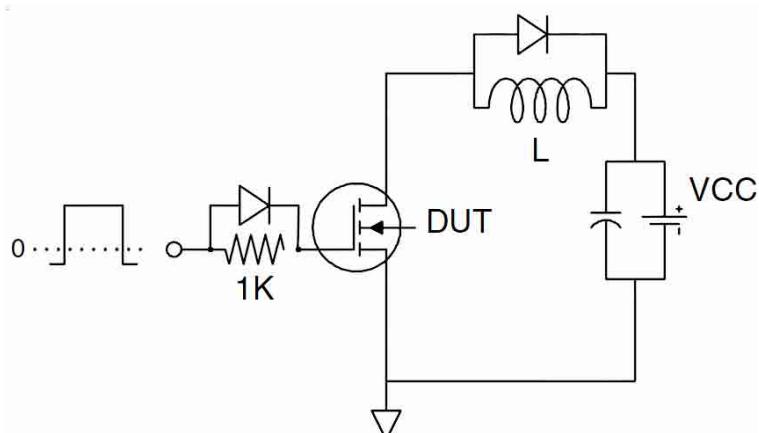
1.Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 1.5%, R_G=25Ω, Starting T_j=25°C

Test Circuit

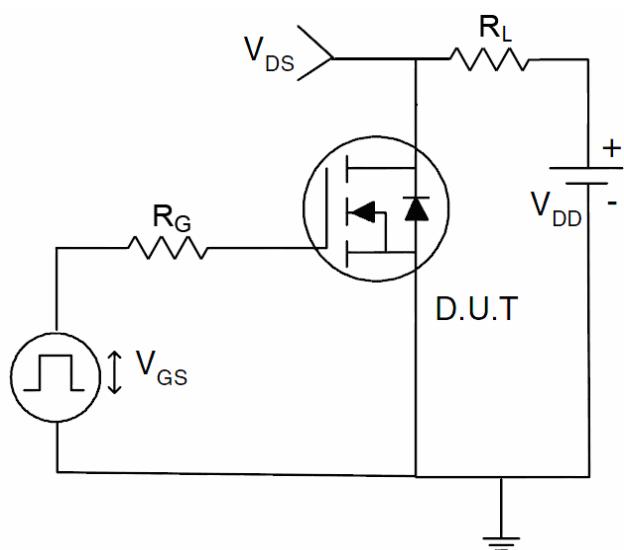
1) E_{AS} test circuit



2) Gate charge test circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (curves)

Figure1. Safe operating area

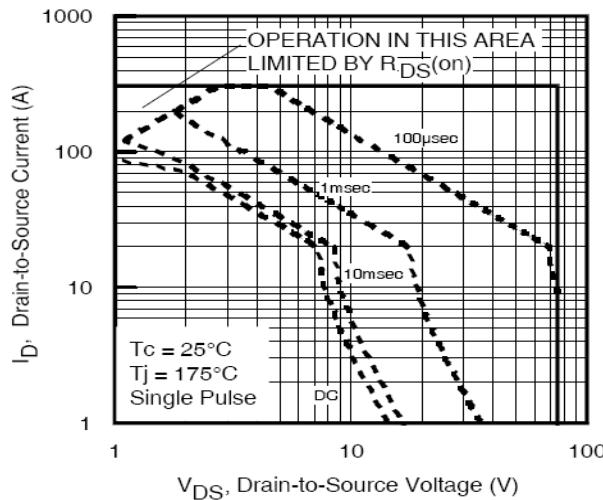


Figure2. Source-Drain Diode Forward Voltage

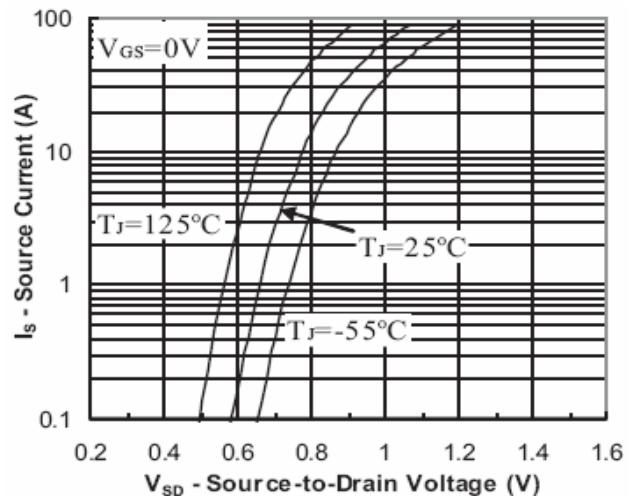


Figure3. Output characteristics

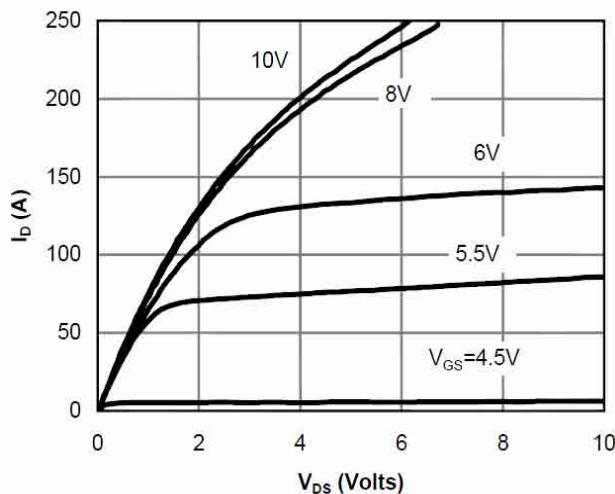


Figure5. Static drain-source on resistance

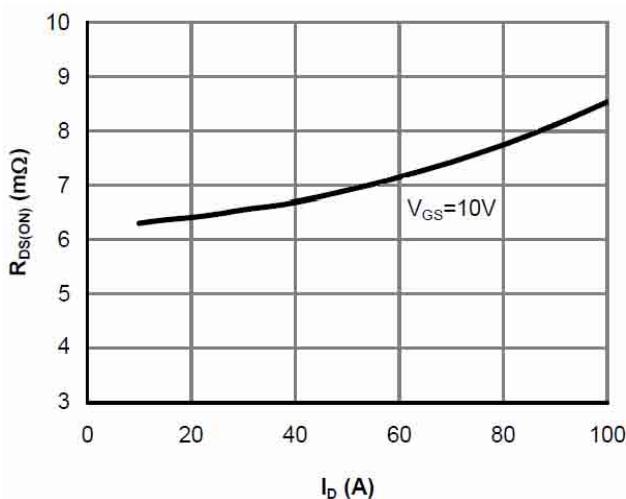


Figure4. Transfer characteristics

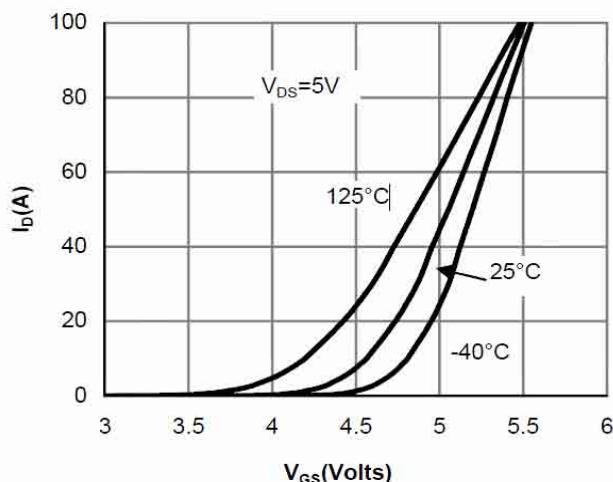


Figure6. $R_{DS(ON)}$ vs Junction Temperature

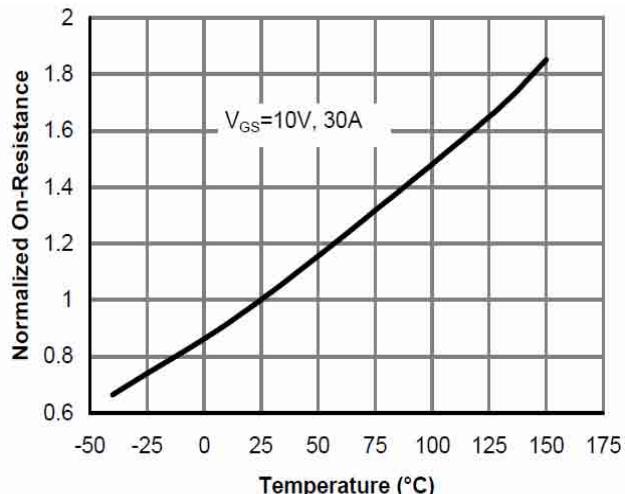
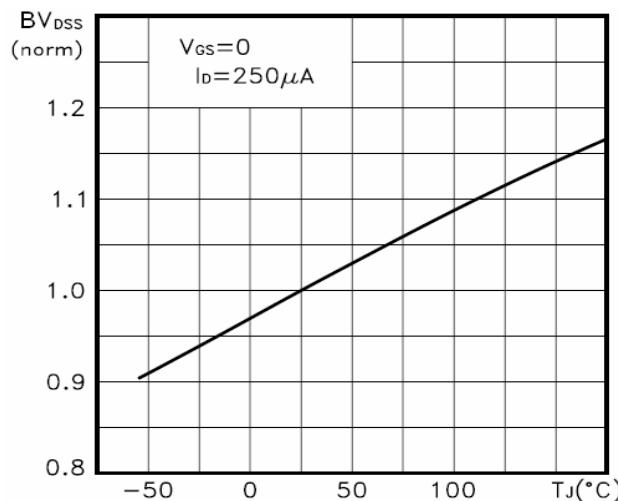
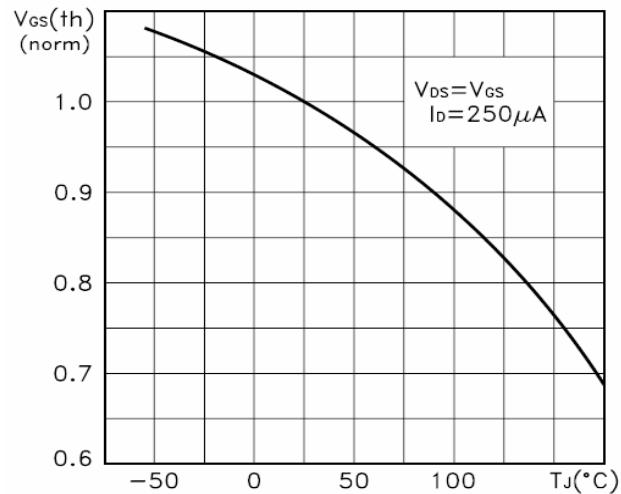
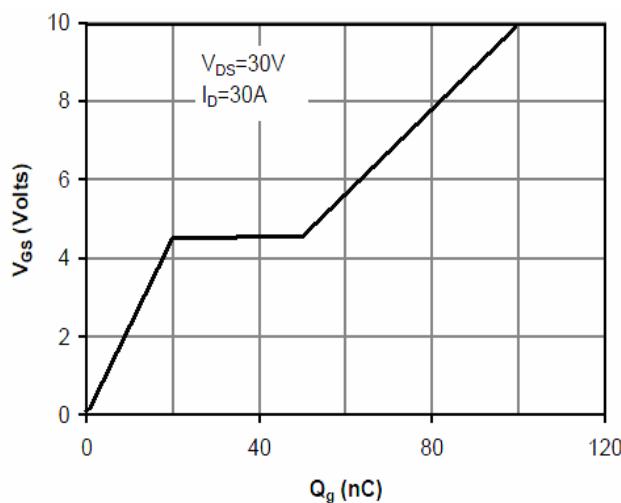
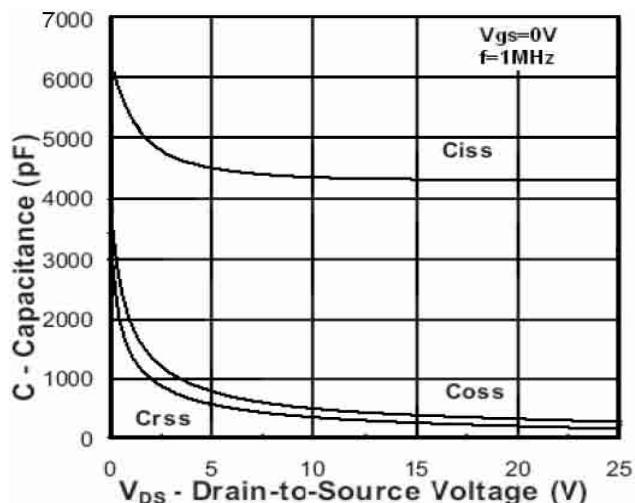
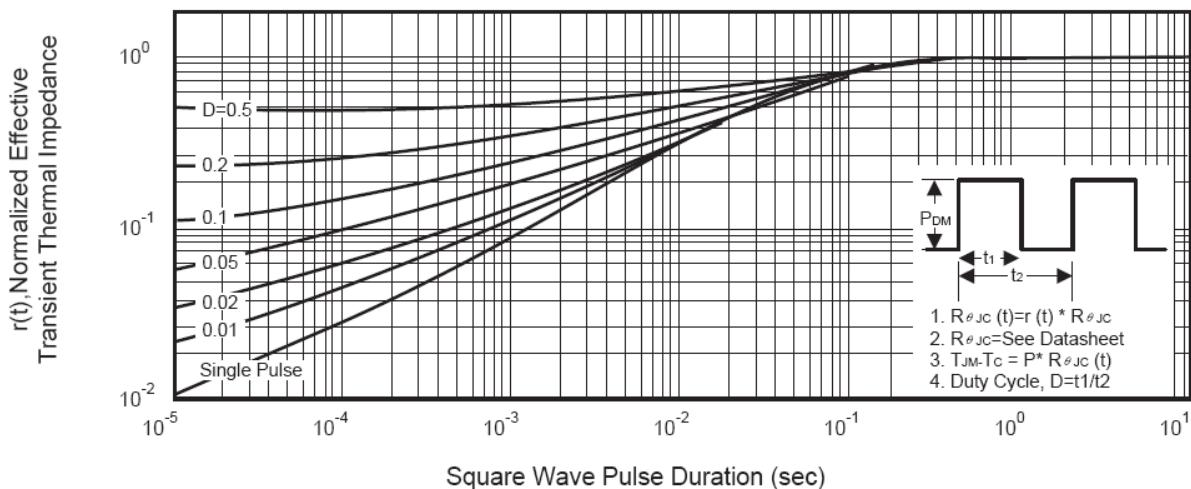
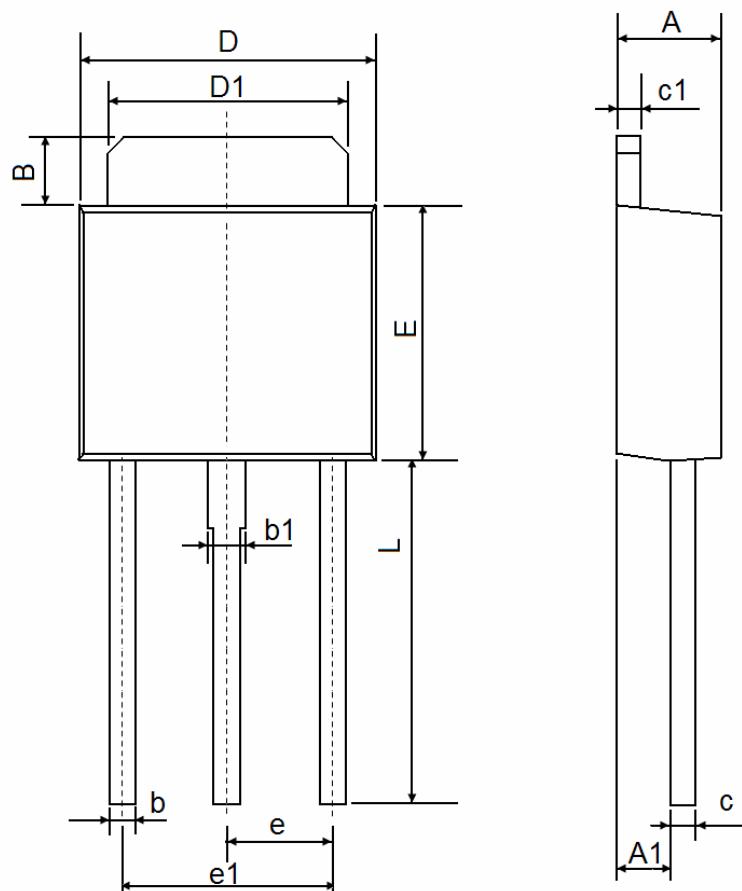


Figure7. BV_{DSS} vs Junction Temperature**Figure8. $V_{GS(th)}$ vs Junction Temperature****Figure9. Gate charge waveforms****Figure10. Capacitance****Figure11. Normalized Maximum Transient Thermal Impedance**

TO-251 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	1.050	1.350	0.042	0.054
B	1.350	1.650	0.053	0.065
b	0.500	0.700	0.020	0.028
b1	0.700	0.900	0.028	0.035
c	0.430	0.580	0.017	0.023
c1	0.430	0.580	0.017	0.023
D	6.350	6.650	0.250	0.262
D1	5.200	5.400	0.205	0.213
E	5.400	5.700	0.213	0.224
e	2.300 TYP.		0.091 TYP.	
e1	4.500	4.700	0.177	0.185
L	7.500	7.900	0.295	0.311